Notice of References Cited Application/Control No. 10/072,927 Examiner Yemane M Gerezgiher Applicant(s)/Patent Under Reexamination LU ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

					· · · · · · · · · · · · · · · · · · ·
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,798,647 B2	09-2004	Dickie, James P	361/683
*	В	US-6,763,458 B1	07-2004	Watanabe et al.	713/100
*	С	US-6,657,654 B2	12-2003	Narayanaswami, Chandrasekhar	348/14.04
*	D	US-2002/0119800 A1	08-2002	Jaggers et al.	455/550
*	E	US-2002/0103008 A1	08-2002	Rahn et al.	455/557
*	F	US-6,266,539 B1	07-2001	Pardo, Teddy	455/556.2
*	G	US-6,161,130 A	12-2000	Horvitz et al.	709/206
*	Н	US-5,999,932 A	12-1999	Paul, Sunil	707/10
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000244555 A	09-2000	Japan	WAKUI, KAZUHIKO	H04L 12/54
	0	JP 10283282 A	10-1998	Japan	ARAI et al.	G06F 13/00
	Р					
	Q					
	R		1			
	s			`		·
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.